

### Performance characteristics

Frequency range: 6-18GHz Small Signal Gain: 18 dB

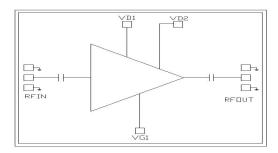
Noise figure: 8dB P-1dB: 24.5dBm Psat: 26dBm

Power supply: +7V/290mA

500hm input/output 100% on-chip testing

Chip size: 1.35 x 1.025 x 0.1 mm

### Functional Block Diagram



### **Product Introduction**

GPA-0618-26 is a broadband high dynamic, low noise, medium power amplifier chip based on GaAs process, with a frequency range of 6GHz~18GHz, a small signal gain of 18dB, and a saturated output power of 26dBm. The chip via metallization process ensures good grounding, and the back side is metallized, which is suitable for eutectic sintering or conductive adhesive bonding process.

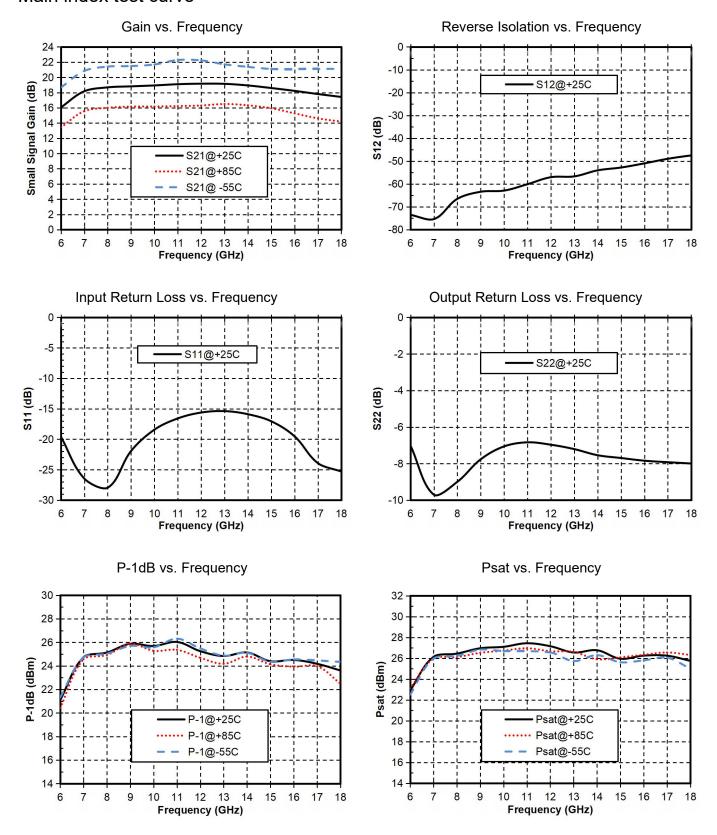
Use restriction parameter <sup>1</sup>				
Maximum drain voltage	+9V			
Maximum gate bias	-3V			
Maximum input power	+15dBm			
Operating temperature	-55 ~ +85°C			
Storage temperature	-65 ~ +150°C			

[1] Exceeding any of these maximum limits may cause permanent damage.

Electrical parameters (TA = +25°C, Vd = +7V)						
index	Minimum	Typical Value	Maximum	unit		
Frequency Range	6-18			GHz		
Small Signal Gain	16	18	19	dB		
Gain Flatness	-	±1.0	-	dB		
Noise Figure		8.0	-			
P-1dB	21	24.5	26	dBm		
Psat	23	27	26.5	dBm		
Input return loss		20		dB		
Output return loss		8		dB		
Quiescent Current		290		mA		
By adjusting the Vg ter	rminal voltage from -	2V to 0V, 290mA can	be achieved.			

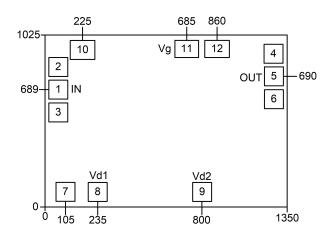


### Main index test curve





# Appearance structure <sup>2</sup>

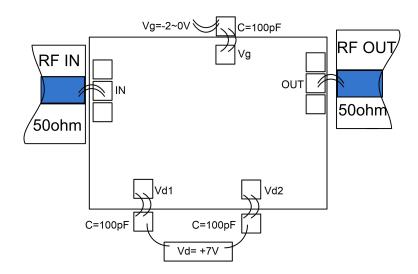


[ 2 ] All units in the figure are micrometers

Bonding point definition					
Bonding point number	Function Symbol	Functional Description	Equivalent Circuit		
1	RFIN	RF signal input terminal, no DC blocking capacitor required.	RFIN		
5	RFOUT	RF signal output terminal, no DC blocking capacitor required.			
8	Vd1	Amplifier drain bias, requires external 100pF bypass capacitor.	- Vee		
9	Vd2	Amplifier drain bias, requires external 100pF bypass capacitor.	Vosa		
11	Vg	Amplifier gate bias, requires external 100pF bypass capacitor.	Vg O		
2, 3, 4, 6, 10, 12	GND	Ground pressure point for probe testing.	GND		
Chip bottom	GND	The bottom of the chip needs to be well grounded to RF and DC.	GND		



### Recommended assembly diagram



#### **Notice**

- The chip must be stored in an anti-static container and kept in a nitrogen environment.
- Do not attempt to clean the bare die surface using wet chemical methods.
- Please strictly follow the ESD protection requirements to avoid static damage to the bare chip.
- General operation: Please use precision pointed tweezers to pick up bare chips. Avoid touching the chip surface with tools or fingers during operation.
- Rack mounting operation suggestions: Bare chip mounting can be done by AuSn solder eutectic sintering or conductive adhesive bonding. The mounting surface must be clean and flat.
- Sintering process: It is recommended to use AuSn solder sheets with a gold-tin ratio of 80/20. The working surface temperature reaches 255 °C and the tool (vacuum chuck) temperature reaches 265 °C. When the high-temperature mixed gas (nitrogen-hydrogen ratio of 90/10) is blown to the chip, the temperature at the top of the tool should be raised to 290 °C. Do not let the chip exceed 320 °C for more than 20 seconds. The friction time should not exceed 3 seconds.
- Bonding process: The amount of conductive glue dispensed should be as small as possible. After the chip is
  placed in the installation position, the conductive glue can be vaguely seen around it. For curing conditions,
  please follow the information provided by the conductive glue manufacturer.
- Bonding operation suggestions: Use Φ0.025mm (1mil) gold wire for both ball and wedge bonding.
  Thermosonic bonding temperature is 150 °C. The pressure of the wedge bonding knife is 40~50gf for ball bonding and 18~22gf for wedge bonding. Use the smallest possible ultrasonic energy. The bonding starts at the pressure point on the chip and ends at the package (or substrate).